

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.

7426-071

APPLICATION NO.

09/487,682

APPLICANT

Fukutomi et al.

FILING DATE

January 19, 2000

GROUP

2825

U.S. PTO
10/042408

01/08/02

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
NB	BA	5,173,766	12/22/92	Long et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
NB	BB	WO 90/13991	11/15/90	PCT				

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

Nema Berezny

DATE CONSIDERED

11-12-03

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
NB	AA	5,216,278	06/01/93	Lin et al.	257	688	
NB	AA	5,467,252	11/1995	Nomi et al.	361	760	
NB	AB	4,688,150	8/1987	Peterson	361	403	
NB	AC	3,878,555	4/1975	Freitag et al.	257	668	
NB	AD	4,376,287	3/1983	Sechi	257	668	
NB	AE	3,748,543	7/1973	Roberson	257	778	
NB	AF	5,381,039	1/1995	Morrison	257	778	
NB	AG	5,579,207	11/1996	Hayden et al.	257	778	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
NB	AH	EP 0391790 A1	10/10/90	Europe				
NB	AI	WO92/21150	11/26/92	PCT				
NB	AJ	EP 0 091 072 A	10/12/83	Europe				
NB	AK	JP 5-129473	5/25/93	Japan				
NB	AL	JP 3-94459	4/19/91	Japan				
NB	AM	59-208756	11/27/84	Japan				

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

NB	AN	Matsuo et al., "Smallest Flip-Chip-Like Package 'Chip Scale Package (CSP)"; The Second VLS Packaging Workshop of Japan, 1994
NB	AO	Nikkei Materials & Technology 94.4 (no. 140)

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ATTY. DOCKET NO.

7426-0082

APPLICATION NO.

10/042,408

APPLICANT

Fukutomi et al.

FILING DATE

January 8, 2002

GROUP

2812

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
NB	AA	JP 59043554	03/10/84	Japan	H01L	23/12	X	
NB	AB	JP 59208756	11/27/84	Japan	H01L	23/12	X	
NB	AC	JP 59231825	12/26/84	Japan	H01L	21/58	X	
NB	AD	JP 60160624	08/22/85	Japan	H01L	21/58	X	
NB	AE	JP 61222151	10/02/86	Japan	H01L	23/12	X	
NB	AF	JP 1289273	11/21/89	Japan	H01L	23/12	X	
NB	AG	JP 2153542	06/13/90	Japan	H01L	21/56	X	
NB	AH	JP 3094430	04/19/91	Japan	H01L	21/50	X	
NB	AI	JP 3094459	04/19/91	Japan	H01L	23/50	X	
NB	AJ	JP4-26545	03/03/92	Japan	H01L	23/12	X	
NB	AK	JP 4072658	03/06/92	Japan	H01L	25/04	X	
NB	AL	JP 4277636	10/02/92	Japan	H01L	21/60	X	
NB	AM	JP 6053383	02/25/94	Japan	H01L	23/50	X	

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